# **TEST REPORT**

Reference No	:	WTD24D10244884W002
FCC ID	:	ZLZRF013B-MR-001
Applicant	:	Shenzhen Mindray BIO-Medical electronics Co.,LTD.
Address	:	Mindray Building, Keji 12th Road South, Hi-tech Ind, Shenzhen China
Manufacturer	:	Shenzhen Nicent Electronic Co.ltd
Address	:	5F- Blk C, No.2, 2nd Industrial Park, Jiazitang, Guangming Dist, Shenzhen, CHN
Product	:	wireless remote control
Model(s)	:	RF013B-MR001
Standards	:	FCC 47CFR Part 2 Subpart J Section 2.1093
Date of Receipt sample	:	2024-10-24
Date of Test	:	2024-10-24 to 2024-11-20

#### Remarks:

**Date of Issue**..... : 2024-12-10

Test Result..... : Pass

The results shown in this test report refer only to the sample(s) tested, this test report cannot be reproduced, except in full, without prior written permission of the company. The report would be invalid without specific stamp of test institute and the signatures of compiler and approver.

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Compiled by:	Approved by:
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Estel Qian / Test Engineer	Deval Qin /Designated Reviewer

Reference No.: WTD24D10244884W002 Page 2 of 7

### 2. Contents

			Page
1	COVI	/ER PAGE	1
2.	CON	ITENTS	2
3.	REVI	ISION HISTORY	3
4.	GENI	IERAL INFORMATION	4
	4.1. 4.2. 4.3. 4.4. 4.5.	DETAILS OF E.U.T. TEST FACILITY SUBCONTRACTED ABNORMALITIES FROM STANDARD CONDITIONS	4 4 4
5.	TEST	T SUMMARY	5
6.	RF E	EXPOSURE	6
	6.1. 6.2. 6.3.	PROCEDURES AND REQUIREMENTS	6

Reference No.: WTD24D10244884W002 Page 3 of 7

## 3. Revision History

Test Report No.	Date of Receipt Sample	Date of Test	Date of Issue	Purpose	Comment	Approved
WTD24D10244884W002	2024-10-24	2024-10-24 to 2024-11-20	2024-12-10	Original	-	Valid

#### Note:

There is no change in the product itself, but the factory been changed and the production process has been updated.

RF exposure was reassessed.

Reference No.: WTD24D10244884W002 Page 4 of 7

#### 4. General Information

#### 4.1. General Description of E.U.T.

Product: wireless remote control

Model(s): RF013B-MR001

Operation Frequency: 2406-2433 MHz

Antenna installation: Internal Antenna

Antenna Gain: 1.50dBi

Note:

#: The antenna gain is provided by the applicant, and the applicant should be responsible for its authenticity, WALTEK lab has not verified the authenticity of its information.

Type of Modulation: FSK
Hardware Version: N/A
Software Version: N/A

#### 4.2. Details of E.U.T.

Ratings: DC 3.0V(2pcs AA Battery)

#### 4.3. Test Facility

The test facility has a test site registered with the following organizations:

ISED CAB identifier: CN0013. Test Firm Registration No.: 7760A.

Waltek Testing Group Co., Ltd. Has been registered and fully described in a report filed with the Industry Canada. The acceptance letter from the Industry Canada is maintained in our files. Registration number 7760A, October 15, 2016.

FCC Designation No.: CN1201. Test Firm Registration No.: 523476.

Waltek Testing Group Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration number 523476, September 10, 2019.

#### 4.4. Subcontracted

☐ Yes ☐ No

If Yes, list the related test items and lab information:

Test Lab: N/A
Lab address: N/A
Test items: N/A

#### 4.5. Abnormalities from Standard Conditions

None.

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Reference No.: WTD24D10244884W002 Page 5 of 7

## 5. Test Summary

Test Items	Test Requirement	Result	
Maximum Permissible Exposure	FCC Part 2.1093	PASS	
(Exposure of Humans to RF Fields)	1 00 1 41( 2: 1000	17.00	

Reference No.: WTD24D10244884W002 Page 6 of 7

### 6. RF Exposure

Test Requirement: FCC 47CFR Part 2 Subpart J Section 2.1093 Evaluation Method: FCC 47CFR Part 1 Subpart I Section 1.1307,

KDB 447498 D01 General RF Exposure Guidance v06

#### 6.1. Procedures and Requirements

According to §15.247 (i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

For 100 MHz to 6 GHz and test separation distances ≤ 50 mm, the 1-g and 10-g SAR test exclusion thresholds are determined by the following:

[(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)]  $\cdot [\sqrt{f(GHz)}] \le 3.0$  for 1-g SAR, and  $\le 7.5$  for 10-g extremity SAR, where

- f(GHz) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm according to 4.1 f) is applied to determine SAR test exclusion.

Routine SAR evaluation refers to that specifically required by § 2.1093, using measurements or computer simulation. When routine SAR evaluation is not required, portable transmitters with output power greater than the applicable low threshold require SAR evaluation to qualify for TCB approval.

#### 6.2. MPE Calculation Method

Result = $P\sqrt{F}/D$ 

P= Maximum turn-up power in mW

F= Channel frequency in GHz

D= Minimum test separation distance in mm

#### 6.3. Radio Frequency Radiation Exposure Evaluation

According to ANSI C63.10:2013 clause 9.5

Calculate the EIRP from the radiated field strength in the far field using Equation (22):

$$EIRP = E_{Meas} + 20\log(d_{Meas}) - 104.7 \tag{22}$$

where

EIRP is the equivalent isotropically radiated power, in dBm

 $E_{\text{Meas}}$  is the field strength of the emission at the measurement distance, in dB $\mu$ V/m

 $d_{\text{Meas}}$  is the measurement distance, in m

NOTE—Because this equation yields the identical result whether the field strength is extrapolated using the default 20 dB/decade of distance extrapolation factor, or the field strength is not extrapolated for distance, this equation can generally be applied directly (with no further correction) to determine EIRP. In some cases, a different distance correction factor may be required; see 9.1.

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Reference No.: WTD24D10244884W002 Page 7 of 7

Frequency(MHz)	E-Field Strength (dBuV/m)	Measurement Distance (m)	EIRP (dBm)	
2406	87.34	3	-7.86	

E-Field Strength maximum refer to test report (Ref. No.: WTD24D10244884W001).

A distance of 5mm normally can be maintained between the user and the device.

Frequency (GHz)	Max EIRP (dBm)	Max Tune-up EIRP (dBm)	Max Tune-up EIRP (mW)	Distance (mm)	Result	Limit
2.406	-7.86	-6.86	0.206	5	0.06391	3

#### **Conclusion:**

No SAR measurement is required.

====End of Report=====